**Elite300™**

Advanced accuracy, precision and performance in an ultra-efficient measurement environment

**Versatile microscope mounts for every application**
- High-stability bridge mount ideal for fine structure probing, using programmable 75 mm (3") X-Y sub-micron transport and 150 mm (6") linear Z lift (motorized and manual transports also available)
- Large-area bridge mount with 300 mm (12") X-Y ideal for array and large-area WLR probing

**Universal accessory mounting system**
- Use with all IV/CV connection panels, vacuum and positioner mounts
- Multiple locations for coax, triax and dual-triax cables
- Fast reconfigurability for multiple test needs

**Patented AttoGuard®**
- Makes the station invisible to your IV and CV instruments
- < 1 fA noise in triaxial IV measurements
- 10 aF resolution CV measurements
- Improved settling time with new thermal isolation

**Large-area Tophat**
- Fast setup in <1 minute
- 20 % increased working area
- Wide 40 mm RF probe-tip separation
- Optimized for all DC and RF measurement probes

**Flexible seals**
- Accommodates up to eight low-noise probe positioners
- Ensures light-tight and EMI integrity

**Quick access control panel for common tasks**

**Patented MicroChamber®**
- Chuck enclosure ensures moisture-free, light-tight EMI-protected measurements, eliminates dark box, making over-temperature measurements easy

**Safety load and unload wafers**
- Full wafer access via locking roll out stage

**Safety interlocks**
- X-Y motion control safety interlock
- IV instrument high-voltage safety interlock

**Adjustable platform height for increased user comfort**

**Small-footprint, fully integrated system**
- Built-in components: motion control, computer controller, anti-vibration and air-management systems

**Unattended testing over multiple temperatures**
- Eliminate the idle time between temperature transitions with VueTrack™ technology
- Minimized thermal drift and reduced die soak with HTS (High-Thermal Stability) enhancements

**Next-generation PureLine™ II**
- 10x better spectral noise (≤ -170 dBVrms/rtHz)
- 4x better system AC noise (≤5 mVp-p)
- Guaranteed shielding effectiveness
- World’s best station for low-level and 1/f measurements

**Powerful automation tools for data collection**
- Automatic wafer alignment
- Auto XYZ and theta correction for sub-micron stepping
- Automatic die size measurement tool

**Fast test and measurement software integration**
- Real-time wafer mapping
- Point-and-shoot navigation
- IEEE, remote communication support

**"Hands-free" microscope remote control**
- With programmable and motorized transports

**Ergonomic accessory mount for system control**

**Ergonomic arm rest for easy sub-micron probing**

**Quick access to auxiliary chucks**
- Two patented auxiliary chucks with vacuum controls
- Temperature-stable HF-CV and RF calibration standards
- Easy probe-tip cleaning using cleaning substrates

**Manual X-Y stage controls**

**Automatic MicroChamber air-purge system**
- Faster thermal transitions and auto dry air-purge controls for "cold" probing

**Patented FemtoGuard® triaxial guarding technology**

**Wide-temperature probing**
- -60 ˚C to 300 ˚C systems for characterization & modeling
- 400 ˚C systems for WLR and power applications
- Stable measurements with thermally optimized platen, MicroChamber and ultra-flat wafer chucks

**Next-generation, semi-automatic stage**
- Fast linear motor/air bearing technology (200 mm/sec)
- Super high-accuracy, temperature-compensating design
- Precision wafer stepping and high-force Z stage

**Optimal test instrument integration**
Instrument shelf available as an option to streamline cabling to the test instruments and to minimize footprint

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